

•General Description

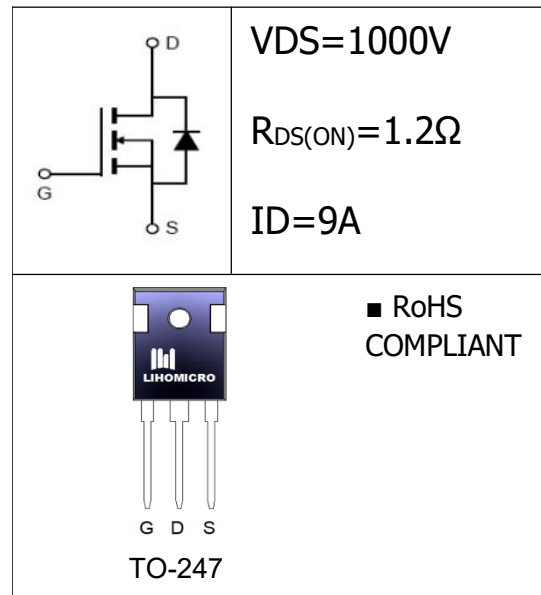
The Power MOSFET LH9N100 has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device offers extremely fast and robust body diode, and is suitable for telecom and power supplies.

•Features

- Low Thermal Resistance
- Fast Switching
- High Input Resistance

•Application

- LED/LCD/PDP TV and monitor Lighting
- Power Supplies


•Ordering Information:

Part number	LH9N100
Package	TO-247
Basic ordering unit (pcs)	330
Normal Package Material Ordering Code	LH9N100T2-TO247-TU
Halogen Free Ordering Code	LH9N100T2-TO247-TU-HF

•Absolute Maximum Ratings (TC =25℃)

PARAMETER		SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage		BV_{DSS}	1000	V
Gate-Source Voltage		V_{GS}	±30	V
Continuous Drain Current	TC = 25℃	I_D	9	A
	TC = 100℃		5.4	
Pulsed drain current (TC = 25℃, tp limited by Tjmax) ¹		I_{DM}	36	A
Single Pulse Avalanche Energy ²		E_{AS}	405	mJ
Power Dissipation(TC=25℃)		P_D	380	W
Junction Temperature		T_J	-55~+150	℃
Storage Temperature		T_{STG}	-55~+150	℃

●Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	1000	1100	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.5	--	4.5	V
Drain-source On Resistance ³	$R_{DS(ON)}$	$V_{GS}=10V, I_D=6A$	--	1.2	1.4	Ω
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=1000V, V_{GS}=0V, T_J=25^\circ C$	--	--	10	μA
		$V_{DS}=1000V, V_{GS}=0V, T_J=125^\circ C$	--	--	250	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 30$	--	--	± 10	μA
Forward Transconductance ³	g_{fs}	$V_{DS}=15V, I_D=6A$	--	15	--	S
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=25V$ $f=1.0MHz$	--	3200	--	pF
Output Capacitance	C_{oss}		--	250	--	
Reverse transfer Capacitance	C_{rss}		--	20	--	
Turn -Off Delay Time ³	$T_d(off)$	$V_{DD}=600V,$ $R_G=25\Omega$	--	51	--	ns
Total Gate Charge	Q_g	$I_D=3A,$ $V_{DS}=960V$ $V_{GS}=10V$ 3	--	80	---	nC
Gate-to-Source Charge	Q_{gs}		--	16	--	
Gate-to-Drain Charge	Q_{gd}		--	42	---	
Continuous Diode Forward Current	I_S		--	--	9.0	A
Pulsed Diode Forward Current	I_{SM}		--	--	36.0	A
Diode Forward Voltage	V_{SD}	$T_J=25^\circ C, I_S=6A$ $V_{GS}=0V$	--	0.9	1.5	V

●Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	0.33	$^\circ C/W$
Thermal Resistance Junction-ambient	R_{thJA}	50	$^\circ C/W$

Notes:

- 1.Repetitive Rating: Pulse width limited by maximum junction temperature.
2. $I_{AS}=9A, V_{DD}=50V, R_G=25\Omega, L=10mH$, Starting $T_J=25^\circ C$
3. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

• **Typical Characteristics**

Fig1 Typical Output Characteristics, $T_c=25^\circ\text{C}$

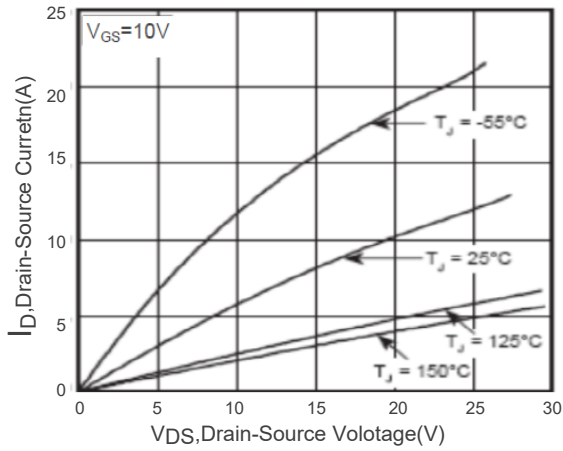


Fig2 On-Resistance Vs. Drain Current and Gate Voltage

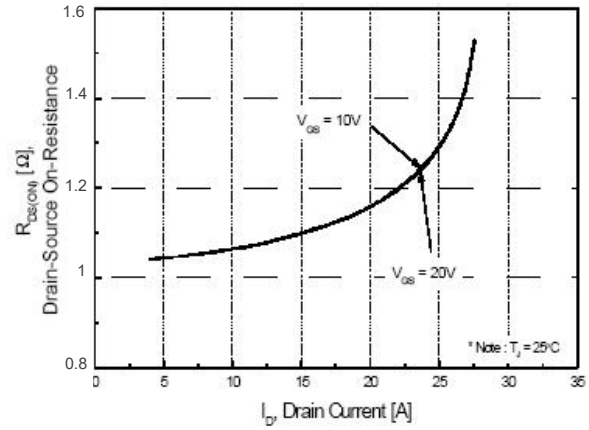


Fig3 Normalized On-Resistance Vs. Temperature

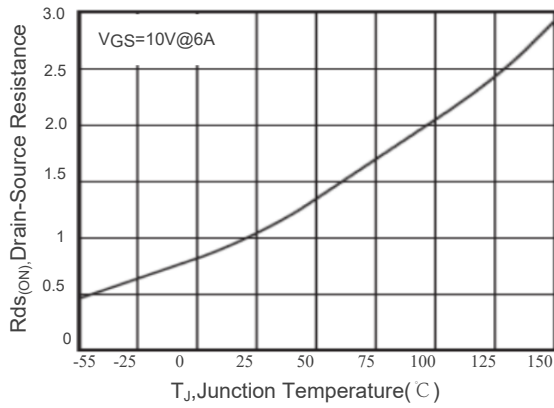


Fig4 Typical Source-Drain Diode Forward Voltage

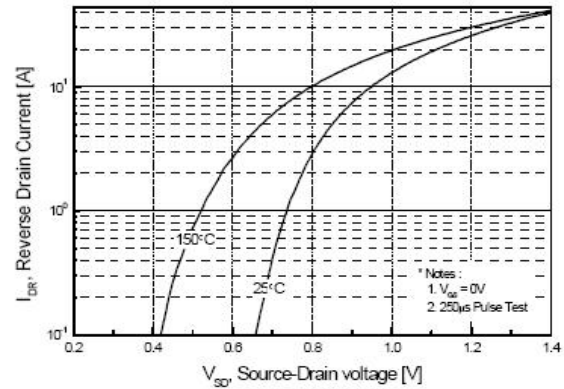


Fig5 Maximum Drain Current Vs. Case Temperature

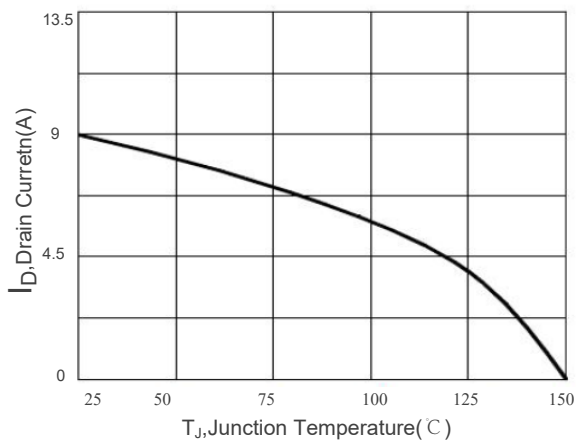
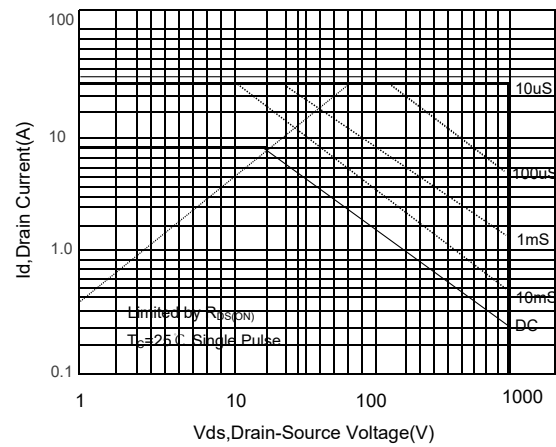


Fig6 Maximum Safe Operating Area



•Typical Characteristics

Fig7 Capacitance vs Drain-Source Voltage

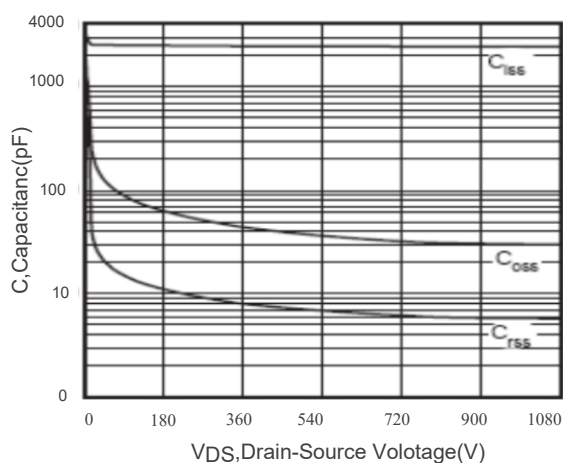


Fig8 Gate Charge vs Gate-Source Voltage

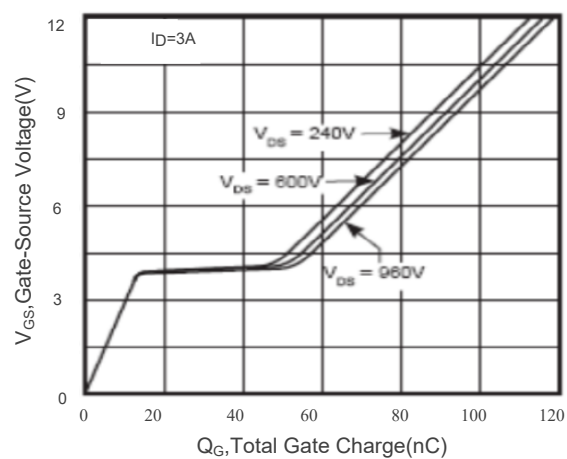
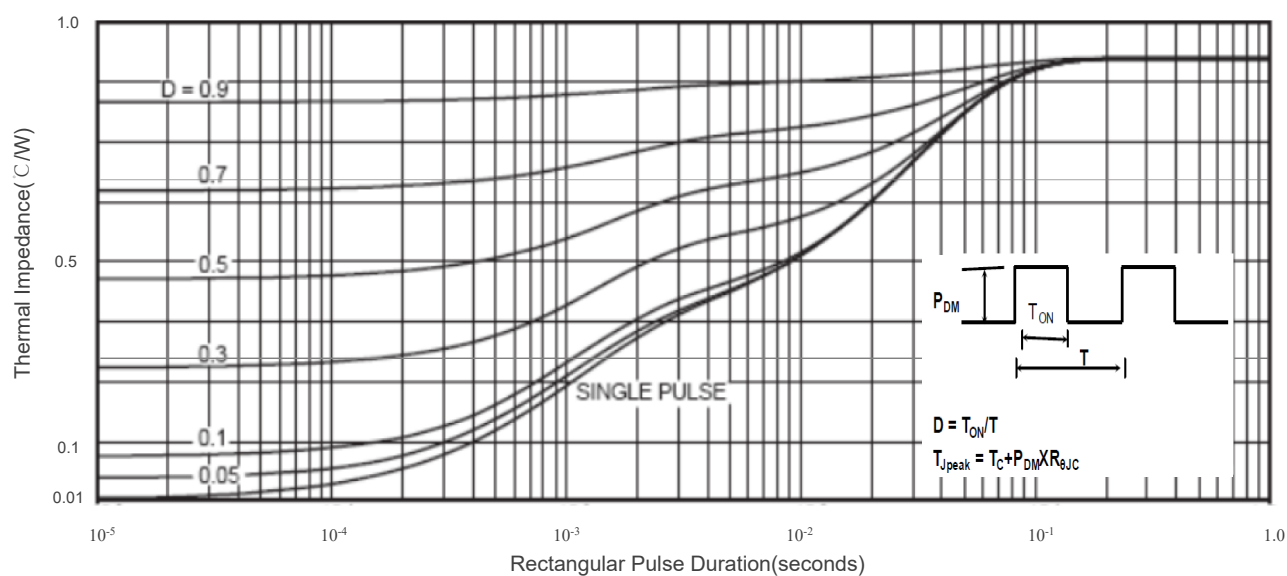


Fig9 Maximum Transient Thermal Impedance



● **Test Circuits & Waveforms**

Fig7. Gate Charge Test Circuit and Waveform

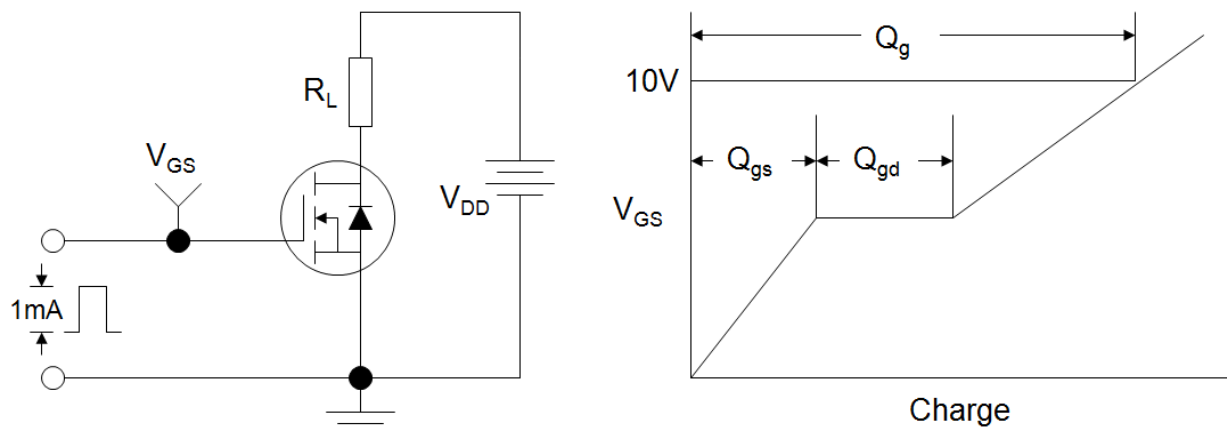


Fig 8. Resistive Switching Test Circuit and Waveform

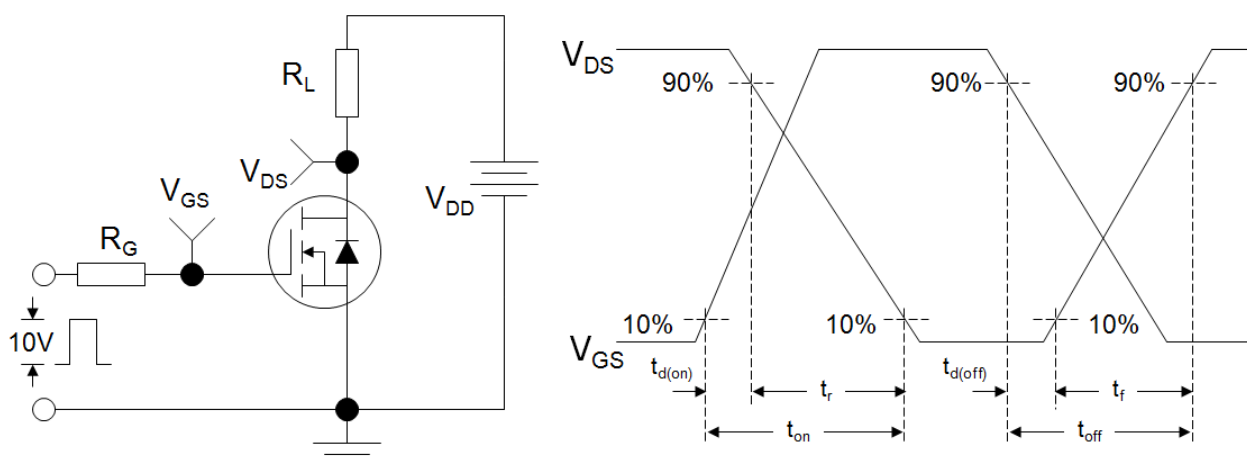
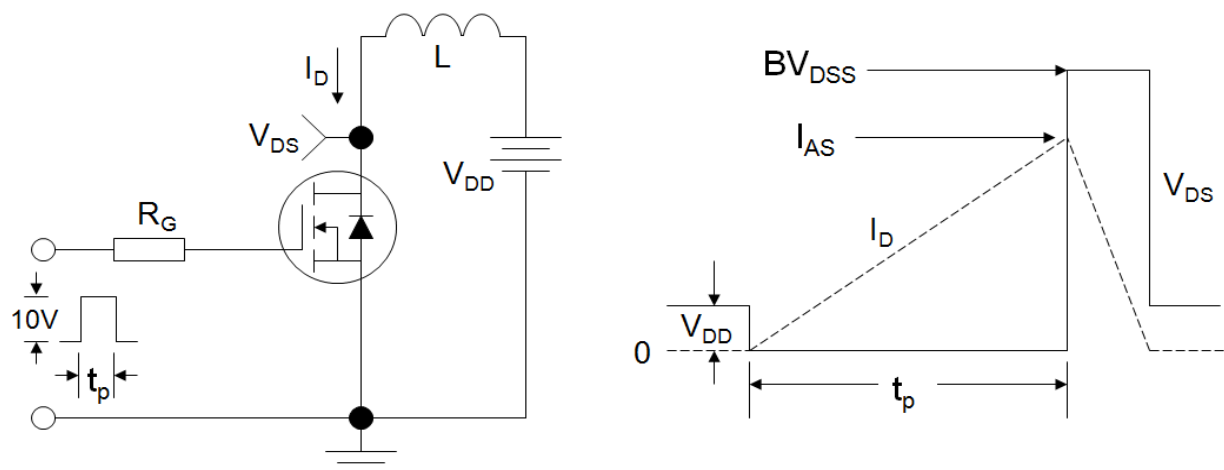


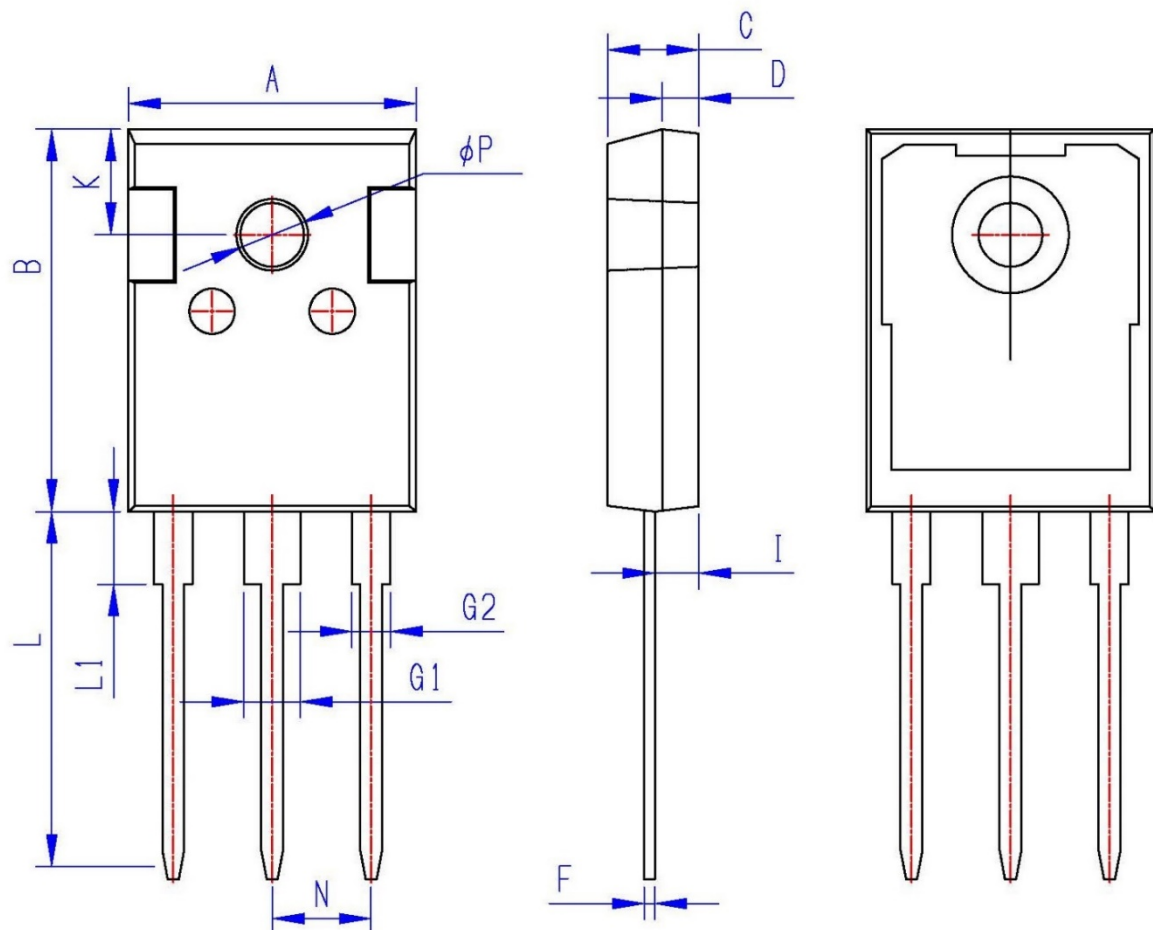
Fig 9. Unclamped Inductive Switching Test Circuit and Waveform



•Dimensions (TO-247)

UNIT:mm

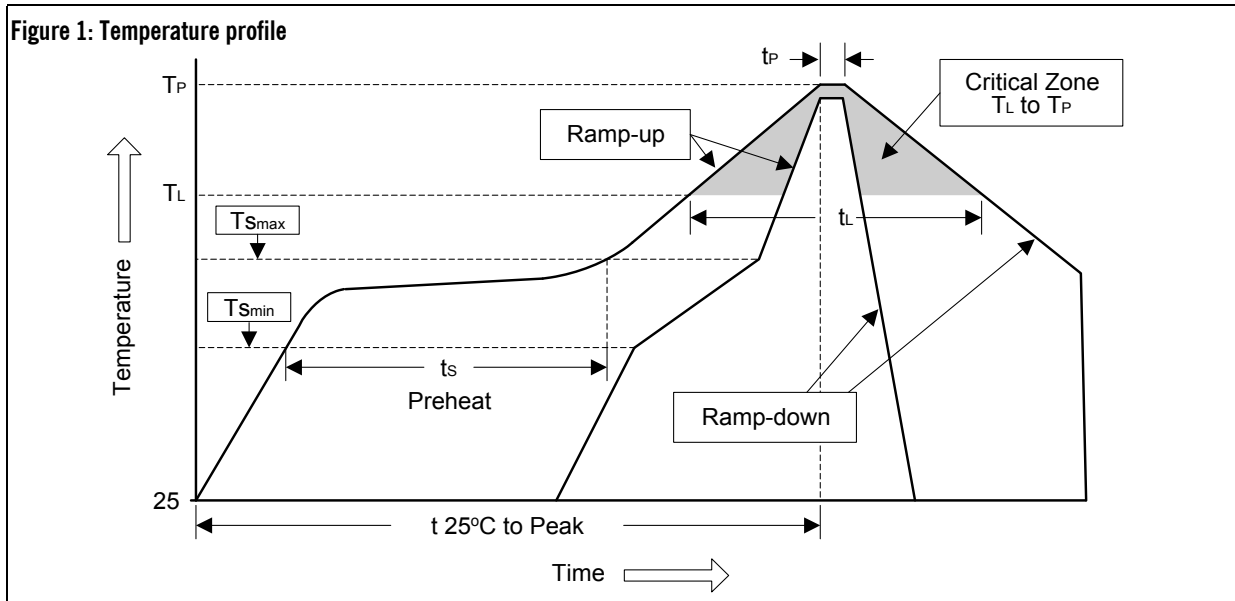
SYMBOL	min	max	SYMBOL	min	max
A	15.60	16.00	G2	1.95	2.25
B	20.80	21.20	N	5.25	5.65
C	4.85	5.15	L1	4.00	4.30
D	1.85	2.15	L	19.60	20.40
E	1.00	1.40	I	2.30	2.50
F	0.50	0.70	ΦP	3.30	3.70
G1	3.00	3.30			



• Soldering Methods for Lihomicro's Products

1. Storage environment: Temperature=10°C to 35°C Humidity=65%±15%
2. Molder Plastic: UL Flammability Classification Rating 94V-0
3. Reflow soldering of surface-mount devices

Figure 1: Temperature profile



● Classification Reflow Profiles

Average ramp-up rate (T_L to T_P)	<3°C/sec	<3°C/sec
Preheat		
- Temperature Min (T_{smin})	100°C	150°C
- Temperature Max (T_{smax})	150°C	200°C
- Time (min to max) (ts)	60 to 120 sec	60 to 180 sec
T_{smax} to T_L		
- Ramp-up Rate	<3°C/sec	<3°C/sec
Time maintained above:		
- Temperature (T_L)	183°C	217°C
- Time (t_L)	60 to 150 sec	60 to 150 sec
Peak Temperature (T_P)	240°C +0/-5°C	260°C +0/-5°C
Time within 5°C of actual Peak Temperature (t_P)	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25°C to Peak Temperature	<6 minutes	<8 minutes

Flow (wave) soldering (solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices.	245°C ±5°C	5sec ±1sec
Pb-Free devices.	260°C +0/-5°C	5sec ±1sec

● Reliability Test Program

Testitem	Method	Description
Solderability	JESD-22,B102	5sec , 245°C
Holt	JESD-22,A108	1000Hrs,Bias@125°C
PCT	JESD-22,A102	168Hrs,100%RH,2atm,121°C
TCT	JESD-22,A104	500Cycles, -65°C ~150°C